

STB70NH03L

N-channel 60V - 0.0075Ω - 70A - D²PAK STripFET™ III Power MOSFET for DC-DC conversion

General features

Туре	V _{DSS}	R _{DS(on)}	۱ _D	
STB70NH03L	30V	< 0.009Ω	60A ⁽¹⁾	

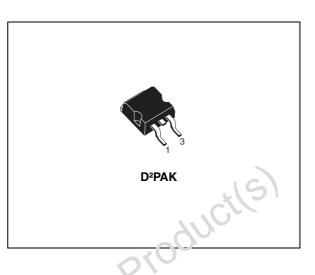
- R_{DS(on)} x Qg industry benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

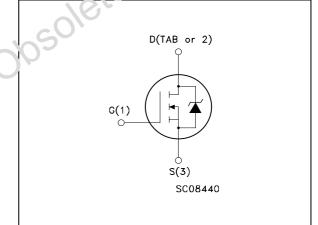
The device utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology. It is ideal in high performance DC-DC converter applications where efficiency is to be achieved at very high output currents.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging	
STB70NH03LT4	B70NH03L	D ² PAK	Tape & reel	

July 2	2006
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Contents

1	Electrical ratings
2	Electrical characteristics 4 2.1 Electrical characteristics (curves) 6
3	Test circuit
4	Package mechanical data 9
5	Packaging mechanical data 11
6	Appendix A
7	Revision history14
obse	Electrical characteristics 4 2.1 Electrical characteristics (curves) 6 6 Test circuit 8 Package mechanical data 9 Packaging mechanical data 11 Appendix A 12 Revision history 14



Electrical ratings

	Table 1.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit			
V _{DS}	Drain-source Voltage ($V_{GS} = 0$)	30	V			
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	30	V			
V _{GS}	Gate- source Voltage	± 20	V			
I _D ⁽¹⁾	Drain Current (continuous) at T _C = 25°C 60					
I _D ⁽¹⁾	Drain Current (continuous) at $T_C = 100^{\circ}C$	43	А			
I _{DM} ⁽²⁾	Drain Current (pulsed) 240					
P _{TOT}	Total Dissipation at $T_C = 25^{\circ}C$ 858					
	Derating Factor					
E _{AS} ⁽³⁾	Single Pulse Avalanche Energy 300					
T _{stg}	Storage Temperature					
TJ	-55 to 175					
1. Value limited by wire bonding						
2. Pulse width	limited by safe oper`ting area					
3. Starting $T_J = 25 \text{ °C}$, ID = 30A, $V_{DD} = 20V$						
10×						
Table 2.	Table 2. Thermal data					
Symbol	Symbol Parameter Value					

Table 2. T	hermal data
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Table 2.	Thermal data		
Symb	ol Parameter	Value	Unit
R _{thJ}	C Thermal resistance junction-case max	1.87	°C/W
R _{thJ} ,	A Thermal resistance junction-ambient max	62.5	°C/W
Tı	Maximum lead temperature for soldering purpose	300	°C
Obsolete f	2100		

Unit

٧

μA

μA

nA

٧

Ω

Ω

Max

1

10

±100

0.009

0.0075 0.0095

0.0135

Min

30

1

 $I_D = 250 \ \mu A$

 $I_{D} = 30 \text{ A}$

 $I_{D} = 30 \text{ A}$

Тур

2 Electrical characteristics

(T_{CASE} = 25°C unless otherwise specified)

Zero gate voltage

Gate-body leakage

Static drain-source on

Current ($V_{DS} = 0$) Gate threshold voltage

resistance

Drain current ($V_{GS} = 0$)

Symbol	Parameter	Test conditions
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250 μA, V _{GS} = 0

 V_{DS} = max rating

 $V_{DS} = max rating$

T_C = 125°C

 $V_{GS} = \pm 20 V$

 $V_{DS} = V_{GS}$

 $V_{GS} = 10 V$

 $V_{GS} = 5 V$

Table 4. Dyna	mic
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IDSS

I_{GSS}

V_{GS(th)}

R_{DS(on)}

	Table 4.	Dynamic					
	Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
	g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 10 V$ $I_{D} = 18 A$		25		S
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 10V$ f = 1 MHz $V_{GS} = 0$		2200 380 49		pF pF pF
	R _G	Gate Input Resistance	f = 1 MHz gate DC bias = 0 test signal level = 20 mV open drain		1.5		Ω
	t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay Time Fall time			21 95 19 15		ns ns
sole	Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} = 15V I _D = 70A V _{GS} = 5V		15.7 8.3 3.4	21	nC nC nC
002	Q _{gls} ⁽²⁾	Third-quadrant gate charge	V _{DS} < 0 V V _{GS} = 10 V		15		nC

1. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %

2. Gate charge for synchronous operation . See Chapter 6: Appendix A



Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				60 240	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 30 \text{ A}$ $V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 60 \text{ A } \text{ di/dt} = 100 \text{ A/} \mu \text{s}$ $V_{DD} = 20 \text{ V} \qquad T_{J} = 150^{\circ}\text{C}$		32 51 3.2		ns nC A

 Table 5.
 Source drain diode

1. Pulse width limited by safe operating area

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %

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2.1 Electrical characteristics (curves)

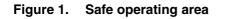
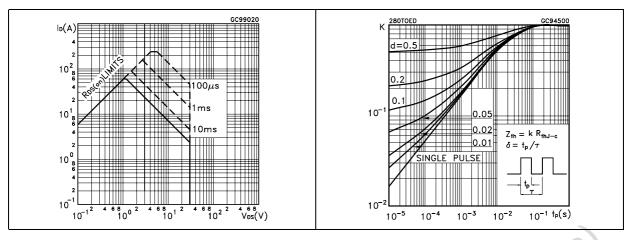
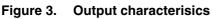


Figure 2. Thermal impedance





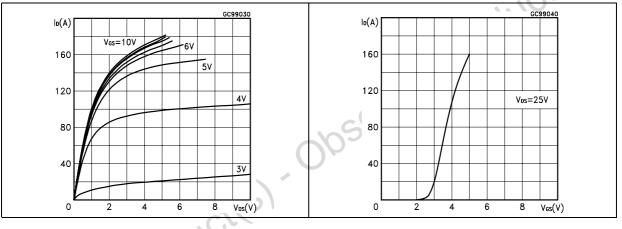
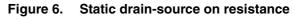
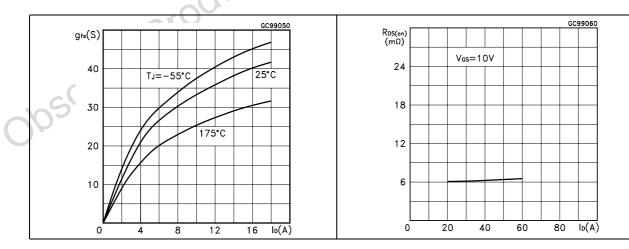


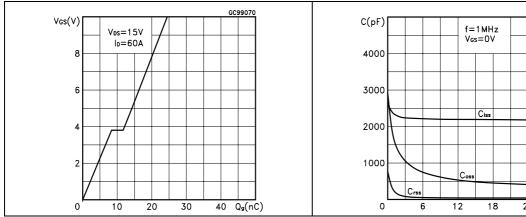
Figure 4.





Transfer characteristics





Gate charge vs gate-source voltage Figure 8. Capacitance variations Figure 7.

Figure 9. Normalized gate threshold voltage vs temperature

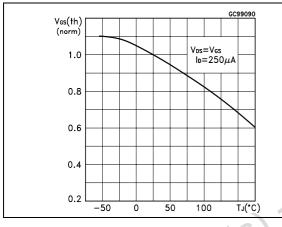


Figure 11. Source-drain diode forward characteristics

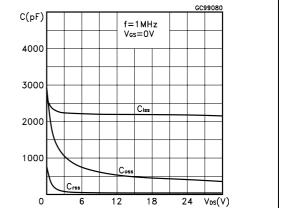


Figure 10. Normalized on resistance vs temperature

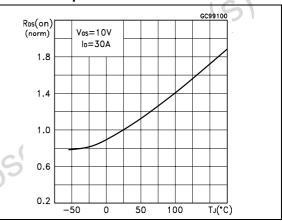
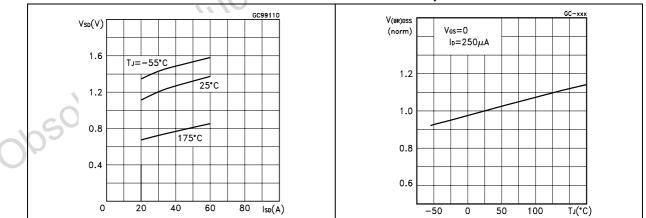


Figure 12. Normalized Breakdown vs temperature



1KΩ

۷_G

SC06000

3 Test circuit

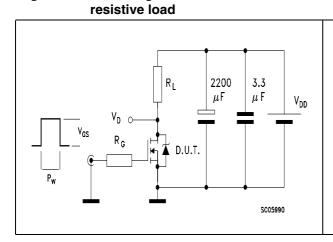
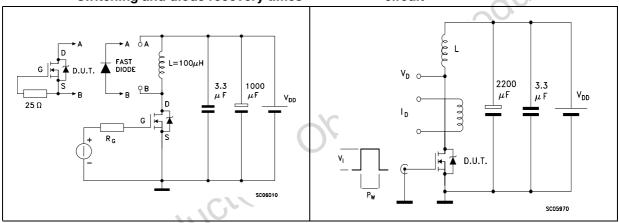
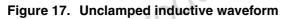


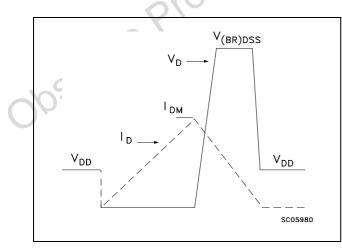
Figure 13. Switching times test circuit for

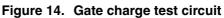
Figure 15. Test circuit for inductive load switching and diode recovery times











12

 $V_i = 20V = V_{GMAX}$

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2200

μÌ

1ΚΩ

I_G=CONST

2.7K Ω

47Κ Ω

100Ω

100nF

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4 Package mechanical data

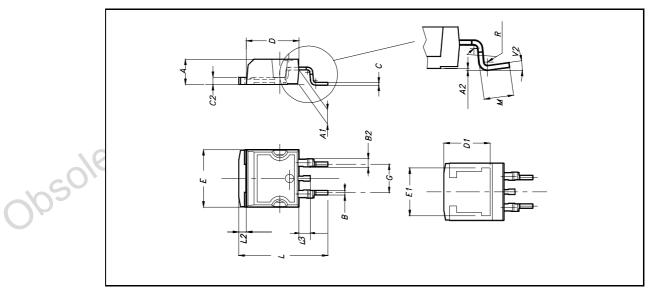
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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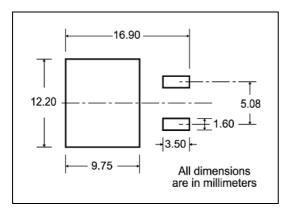
57

DIM.	mm.			inch		
	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX
А	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
В	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
С	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
Е	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
М	2.4		3.2	0.094		0.126
R		0.4			0.015	

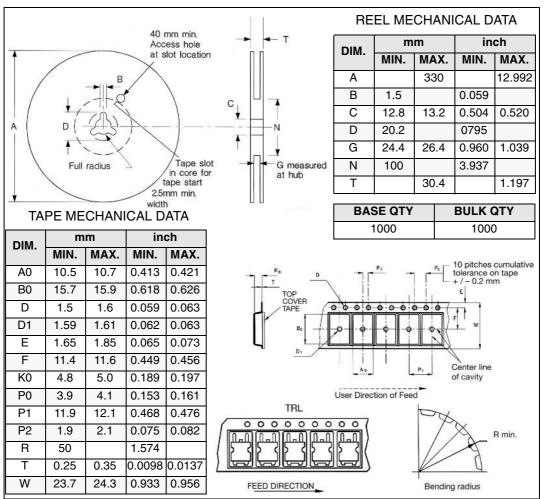




Packaging mechanical data D²PAK FOOTPRINT



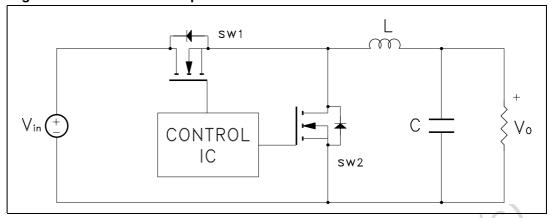
TAPE AND REEL SHIPMENT

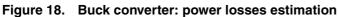


* on sales type

57

6 Appendix A





The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small QgIs to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



10501E



		High side switching (SW1)	Low side switch (SW2)
Pconduction		$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
Pswitching		$V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
Pdiode	Recovery (1)	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
Paloae	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate(Q _G)		$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
P _{Qoss}		$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$

Table 6. Power losses calculation

Table 7. Paramiters meaning

	1. Dissipated by SW1 of Table 7. Param	2 2 during turn-on iters meaning
	Parameter	Meaning
	d	Duty-cycle
	Q _{gsth}	Post threshold gate charge
	Q _{gls}	Third quadrant gate charge
	Pconduction	On state losses
	Pswitching	On-off transition losses
	Pdiode	Conduction and reverse recovery diode losses
26	Pgate	Gate drive losses
SO.	P _{Qoss}	Output capacitance losses
002		



7 Revision history

Table 8.	Revision	history
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Date	Revision	Changes
21-Jun-2004	5	Complete document
20-Jul-2006	6	New template, no content change

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